

**Ruiyun Zhang**  
Chongqing Daqo New Energy Co., Ltd.  
Apr. 24, 2009



**SECONDARY ION MASS SPECTROMETRY  
ANALYTICAL REPORT**

**Job# H08W2929**

Apr. 24, 2009

Prepared by:

A handwritten signature in black ink, appearing to read 'Hongyan Liu', written in a cursive style.

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## SECONDARY ION MASS SPECTROMETRY ANALYTICAL REPORT

### Analytical Request

The purpose of this analysis is to measure SIMS bulk B, P, C, O, Al, Ga, As, Sb, Fe, Mg, Ca, Cu, Ag in Si.

### Results and Discussion

Your data is enclosed.

### Quantification

<i>Element</i>	<i>Quantification†</i>
B, P, C, O, Al, Ga, As, Sb, Fe, Mg, Ca, Cu, Ag	Concurrent analysis of Si standard

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**SIMS Bulk Analysis Results**

**EAG Job:**

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**Concentration (atoms/cm<sup>3</sup>)**

Sample ID.	B	P	C	O	Al	Ga	As	Sb	Fe	Mg	Ca	Cu	Ag
D1	9.61E+13	3.78E+14	1.01E+17	<5e16	<2e13	<7e13	<1e13	<9e13	<5e13	<1e12	<5e12	<5e13	<8e13
Detection limits	1E+13	5E+13	2E+16	5E+16	2E+13	7E+13	1E+13	9E+13	5E+13	1E+12	5E+12	5E+13	8E+13



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**SIMS Bulk Analysis Results**

**EAG Job:**

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**Concentration (atoms/cm<sup>3</sup>)**

Sample ID.	B	P
E1	6.04E+13	1.34E+14
Detection limits	1E+13	5E+13

*Hongyan Liu*

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